Special Issue

Computer Vision and Pattern Recognition Based on Remote Sensing

Message from the Guest Editors

This Special Issue showcases cutting-edge research on the development of novel algorithms, frameworks, and applications that leverage remote sensing data for visual analysis, object recognition, scene comprehension, and change detection. The contributions will cover a wide range of topics, including but not limited to:

- Image processing for remote sensing;
- Object recognition and instance segmentation;
- Defect detection in industrial surfaces;
- Cross-domain object detection;
- Multimodal detection for autonomous driving;
- Advanced network architectures for remote sensing image analysis.

Guest Editors

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Dr. Qi Hu

Prof. Dr. Yudong Zhang

Deadline for manuscript submissions

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Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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